

Accurate and Efficient WLR Test

Intrinsic Wafer Level Reliability (WLR) testing is a valuable tool for semiconductor manufacturers, with several key benefits to complement traditional Package-Level Reliability (PLR) testing:

- Eliminates packaging step
- Analyzes devices weeks earlier
- Can be applied to fully- or partially-processed wafers
- More naturally supports spatial correlation
- Higher yield by eliminating potential ESD damage related to dicing, bonding and package handling

Accurate and efficient WLR tests achieve:

- Shorter product development cycle
- Improved competitive potential in a crowded global marketplace

To maximize the benefits of WLR test, the test instrumentation, probe card, and probing system must work together seamlessly to provide:

- A comprehensive suite of applications
- Precise electrical and thermal biases
- Accurate device measurements
- Repeatable probe placement
- Long-term contact stability
- High parallel capacity
- Automated, unattended operation

With decades of innovation and expertise, Cascade Microtech and Celadon address the need for a sophisticated, high-performance WLR test solution for current and leading-edge semiconductor technologies.



Cascade Microtech is a leader in precision measurement and test of ICs, MEMS, 3D TSV, LED devices and more. Our leading-edge test solutions deliver precision accuracy and superior performance both in the lab and during production manufacturing of high-performance devices.

With a unique scalable architecture, Cascade Microtech reliability test systems offer true parallel test for a wide variety of semiconductor reliability applications.

URL: www.cascademicrotech.com
Email: info@cascademicrotech.com
Phone: 1-503-601-1000



Celadon Systems manufactures ultra high-performance probe cards. Our patented crash-resistant ceramic cards are designed for unparalleled precision, low leakage, and sustained reliability for tests including modeling and characterization, multi-site wafer-level reliability, and parametric test.

URL: www.celadonsystems.com
Email: info@celadonsystems.com
Phone: 1-952-232-1700

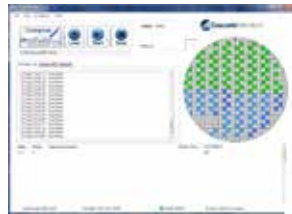
Contact Us For WLR Test Products

Cascade Microtech's Symphony™ WLR test system provides a fully- automated, zero-footprint test solution when integrated with a probe station.

- Software coordinates and monitors Symphony and prober activities for continuous, unattended testing
- Supports all test applications
- Multi-site or single site testing
- Real-time data and wafer maps
- Expands up to 8 rack-mounted systems for high-parallelism testing



Software provides real-time data and wafer maps



Contact Cascade Microtech: SalesRTP@cmicro.com

Celadon offers multiple probe card solutions for multi-site WLR testing, including:

- T90 Series probe card, compatible with a standard 4.5" probe card holder, capable of fA-level measurements and can be configured with up to 500 probes
- TV19 VersaTile probe card, compatible with 4.5", 200 mm, or 300 mm adapters, and can be configured with up to 32 probes per card
- T200 and T300 Buttontile probe cards, capable of probing the entire wafer for fA-level measurements, with up to 5,000 probes on a 200 mm T200 or 10,000 probes on a 300 mm T300



Contact Celadon: info@celadonsystems.com



Cascade Microtech's CM300 is a flexible on-wafer probe system that provides high-integrity data and hands-off productivity.

- Scalable from semi- to fully-automated probe system
- Automated Test Management for small pad probing down to 30 μm
- Fast delivery of precise model parameters to enhance process and device development
- Velox™ probe station control software for fast wafer loading and easy test automation

Contact Cascade Microtech: info@cascademicrotech.com